

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BONALLE ET AL.	
		10/710,325	Examiner	Art Unit Daniel I. Walsh

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0173791	08-2006	Mann et al.	705/074
*	B	US-5,838,812	11-1998	Pare et al.	382/115
*	C	US-2005/0165684	07-2005	Jensen et al.	705/044
*	D	US-2003/0120626	06-2003	Piotrowski, Tony	707/1
*	E	US-2003/0112120	06-2003	K., Seifert Mark	340/5.53
*	F	US-2002/0190124	12-2002	Piotrowski, Tony E.	235/382
*	G	US-4,453,074	06-1984	Weinstein, Stephen B.	705/66
*	H	US-2004/0052406	03-2004	Brooks, Juliana H. J.	382/115
*	I	US-2002/0062291	05-2002	Zoka, Ron	705/64
*	J	US-6,928,181	08-2005	Brooks, Juliana H. J.	382/115
*	K	US-6,591,249	07-2003	Zoka, Ron	705/18
*	L	US-2005/0211784	09-2005	Justin, Antony Manoj	235/492
*	M	US-6,480,825	11-2002	Sharma et al.	704/270

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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	X	

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<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BONALLE ET AL.	
		Examiner Daniel I. Walsh	Art Unit 2876	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
*	B	US-6,104,922	08-2000	Baumann, William John	455/410
*	C	US-2002/0191816	12-2002	Maritzen et al.	382/115
*	D	US-2005/0065872	03-2005	Moebs et al.	705/038
*	E	US-6,257,486	07-2001	Teicher et al.	235/380
*	F	US-2004/0043566	03-2004	Parekh et al.	438/269
*	G	US-2005/0033687	02-2005	Beenau et al.	705/039
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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